

# **TRANSFORMING YIELD INFORMATION OF A SEMICONDUCTOR FABRICATION PROCESS**

## **ABSTRACT**

Publishable yield information can be produced by obtaining an actual yield value associated with an integrated circuit (IC) or portion of an IC formed on each one of a plurality of wafers using a semiconductor wafer fabrication process. An average yield value associated with a plurality of ICs or portions of an IC formed on each one of the plurality of wafers using the semiconductor fabrication process is determined. A transformed yield value associated with the IC or portion of an IC is generated using the actual yield value and the average yield value.